Day One Wednesday, April 5, 2006			
08:00 - 08:30 Continental Breakfast (NIST Cafeteria)			
08:30 - 09:00		Welcome - Opening Remarks Marty Herman, Vladimir Dvornychenko NIST	
09:00 - 10:20	Needs and Applications	Latent Processing at the FBI/LPU Stephen Meagher, FBI/LPU Military Latent Needs Kasey Wertheim, DoD Biometrics Support Contractor, Lockheed Martin Need for Rapid Turnaround at US-VISIT Danny Greathouse, DHS/US-VISIT Support Contractor Need for AFIS Vendors to Improve Search Capability Thomas Smith, LA Sheriff Dept. Problems Experienced with Livescans Francis P. Senese, Joliet, IL, Forensic Science Laboratory	
10:20 - 10:40 Break			
10:40 - 11:40	Needs and Applications	Needs and Applications of Latents at FBI/CJIS B. Scott Swann, FBI/CJIS Applications ULW at DHS Deborah Leben, DHS/USSS Needs and Applications of Latents at CA Dep't. Of Justice Gordon Low, CA Department of Justice	
11:40 - 11:50	Break		
11:50 - 12:50	Needs and Applications	Needs and Applications of Latents at King County, WA, Sheriff Jeri Eaton and Wade Petroka, King County, WA, Sheriff Office Evaluating Automated Finger and Palm Mark (Latent) Searching Ambika Suman, PITO, UK	
	Ne Apr	Implementation of a Remote Latent Search Capability at Interpol Mark Branchflower, Interpol	
12:50 - 13:50	Lunch (NIST (Mark Branchflower, Interpol	
12:50 - 13:50 13:50 - 15:00		Mark Branchflower, Interpol	
	Lunch (NIST (Mark Branchflower, Interpol Cafeteria) Experience in Lights-out Processing Jean-Christophe Fondeur, Sagem-Morpho Maximizing Latent Identification Performance Wally Briefs, Cogent Threshold and Parameters for Automatic Decisions	
13:50 - 15:00	Capabilities Decisions	Mark Branchflower, Interpol Cafeteria) Experience in Lights-out Processing Jean-Christophe Fondeur, Sagem-Morpho Maximizing Latent Identification Performance Wally Briefs, Cogent Threshold and Parameters for Automatic Decisions	

Day Two Thursday, April 6, 2006			
08:00 - 08:30 Continental Breakfast (NIST Cafeteria)			
08:30 - 09:30	Capabilities Features	CDEFFS Extended Feature Sets Austin Hicklin, Mitretek High Resolution Fingerprint Matching Using Level 3 Features Anil Jain and Yi Chen, Michigan State University Level 3 Feature Detection Using Support Vector Machines Phillip Wasserman, NIST	
09:30 -09:50 Break			
09:50 - 10:50	Image Quality	Quality Measure Workshop Lessons Learned Elham Tabassi, NIST Latent Quality Measures Kasey Wertheim, DoD Biometrics Support Contractor, Lockheed Martin Quantifying Latent Quality Austin Hicklin, Mitretek	
10:50 - 11:10	Break		
11:10 - 12:30	Evaluation Methods	Lessons Learned During IAFIS Source Selection George Kiebuzinski, Mitretek Offline Biometric Testing at NIST Patrick Grother, NIST Test Sets at NIST Stephen Wood, NIST Proposed Latent Testing Methodology Mike Garris, NIST	
12:30 - 13:40	Lunch (NIST Cafeteria)		
13:40 - 15:30	Discussions	Open Forum 1) Methods of Evaluating Latent Algorithms 2) Extended Feature Sets	